

200V N-Channel MOSFET

Description

P50N20-MNS, the silicon N-channel Enhanced MOSFETs, is obtained by advanced MOSFET technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor is suitable device for SMPS, high speed switching and general purpose applications

FEATURES

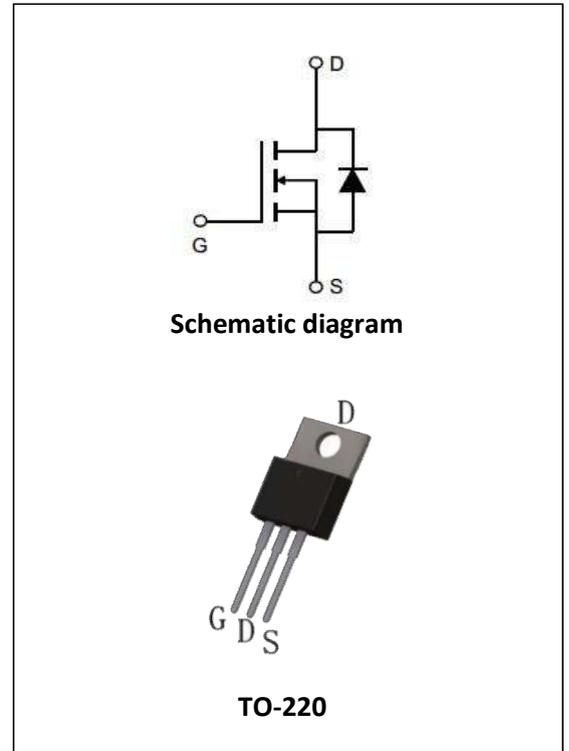
- ① Proprietary New Planar Technology
- ② $R_{DS(ON),typ.}=47m\Omega@V_{GS}=10V$
- ③ Low Gate Charge Minimize Switching Loss
- ④ Fast Recovery Body Diode

APPLICATIONS

- ① DC-DC Converters
- ② DC-AC Inverters for UPS
- ③ SMPS and Motor controls

Package Marking And Ordering Information:

Ordering Codes	Package	Product Code	Packing
P50N20-MNS	TO-220	P50N20	Tube



Absolute Maximum Ratings $T_c = 25^\circ C$, unless otherwise noted				
Parameter	Symbol	Value		Unit
		TO-220		
Drain-Source Voltage	V_{DSS}	200		V
Continuous Drain Current	I_D	50		A
Pulsed Drain Current (note1)	I_{DM}	180		A
Gate-Source Voltage	V_{GSS}	± 20		V
Single Pulse Avalanche Energy (note1)	E_{AS}	191		mJ
Avalanche Current (note1)	I_{AS}	31		A
Repetitive Avalanche Energy (note1)	E_{AR}	124		mJ
Power Dissipation ($T_C = 25^\circ C$)	P_D	63.7	104	W



Operating Junction and Storage Temperature Range		T_J, T_{stg}	-55~+150			°C
Thermal Resistance						
Parameter	Symbol	Value			Unit	
		TO-220				
Thermal Resistance, Junction-to-Case	R_{thJC}	1.2			°C/W	
Thermal Resistance, Junction-to-Ambient	R_{thJA}	60				
Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Value			Unit
			Min	Typ	Max	
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	200	230	--	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=200V, V_{GS} = 0V, T_J= 25^\circ\text{C}$	--	--	1	μA
		$V_{DS}=200V, V_{GS}=0V, T_J= 125^\circ\text{C}$	--	--	100	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0V$	--	--	± 100	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	--	4.0	V
Drain-Source On-Resistance (Note4)	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 20A$	--	47	52	m Ω
Forward Transconductance (Note4)	g_{fs}	$V_{DS} = 25V, I_D = 20A$	--	16	--	S
Dynamic						
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=25V, f=1.0\text{MHz}$	--	2800	--	μF
Output Capacitance	C_{oss}		--	355	--	
Reverse Transfer Capacitance	C_{rss}		--	101	--	
Total Gate Charge	Q_g	$V_{DD} = 160V, I_D = 52A,$	--	154	--	nC
Gate-Source Charge	Q_{gs}		--	13	--	
Gate-Drain Charge	Q_{gd}		--	58	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD}=160V,$ $I_D=52A,$ $V_{GS} = 15V.$ $R_G=25\Omega$	--	46	--	ns
Turn-on Rise Time	t_r		--	54	--	
Turn-off Delay Time	$t_{d(off)}$		--	360	--	
Turn-off Fall Time	t_f		--	96	--	
Drain-Source Body Diode Characteristics						
Continuous Source Current	I_{SD}	Integral PN-diode in MOSFET	--	--	50	A
Pulsed Source Current	I_{SM}		--	--	180	



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P50N20-MNS

Body Forward Voltage	V_{SD}	$I_S = 20A, V_{GS} = 0V$	--	--	1.4	V
Reverse Recovery Time	t_{rr}	$V_{GS} = 0V, I_F = 10A,$ $diF/dt = 100A / \mu s$	--	152	--	ns
Reverse Recovery Charge	Q_{rr}		--	1	--	μC

Notes:

- 1.Repetitive Rating: Pulse width limited by maximum junction temperature
- 2.L=1mH, $V_{DD}=30V$, $R_G=25\Omega$, Starting $T_J=25^\circ C$
- 3.Pulse Test: Pulse width $\leq 300\mu s$, Duty Cycle ≤ 1

Figure 1 Safe Operating Area

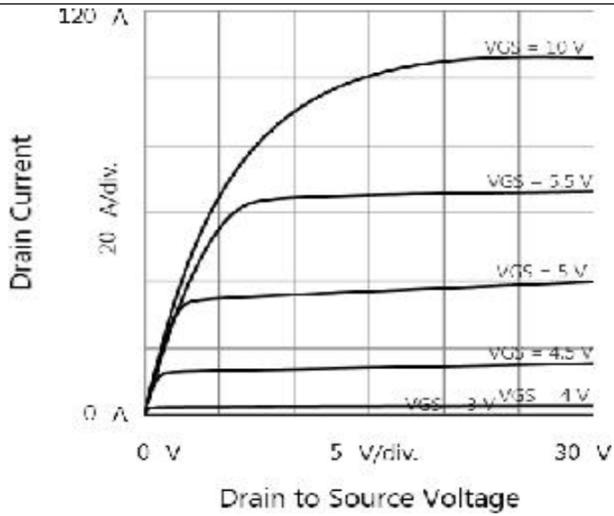


Figure 2 Max Thermal Impedance

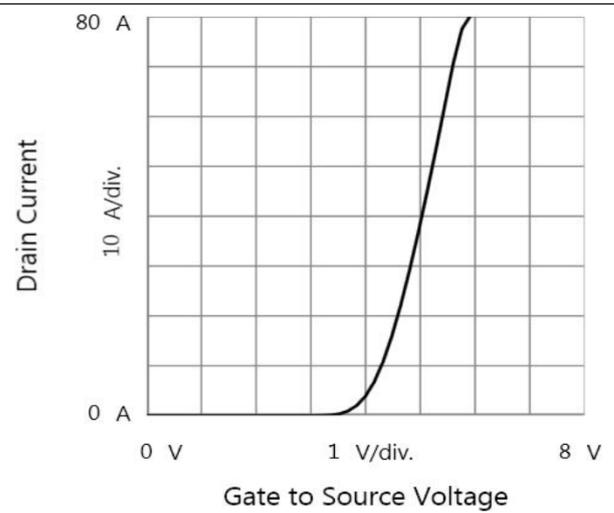


Figure 3. Drain to Source Resistance vs. Drain Current

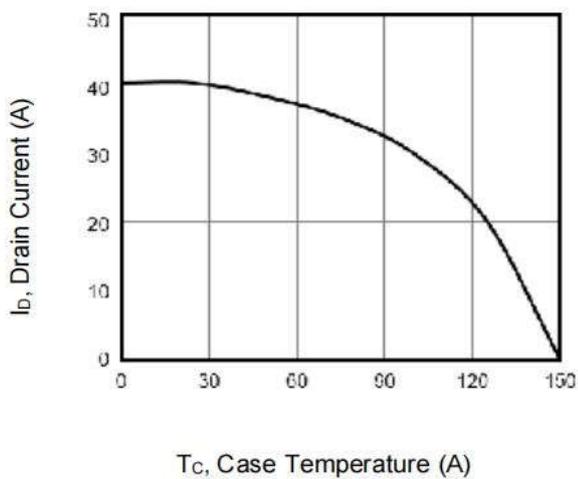


Figure 4. BV_{DSS} Variation vs. Temperature

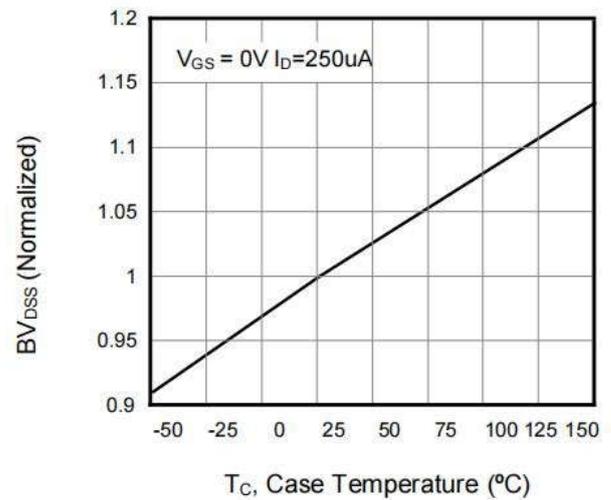


Figure 5. Drain to Source Voltage vs. Gate to Source Voltage

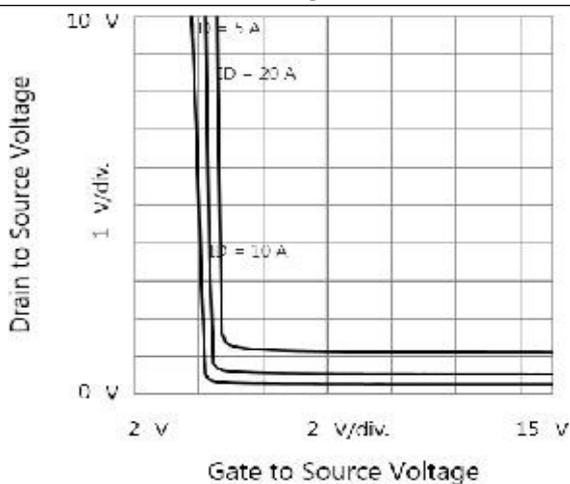


Figure 6. Body Diode Forward Characteristics

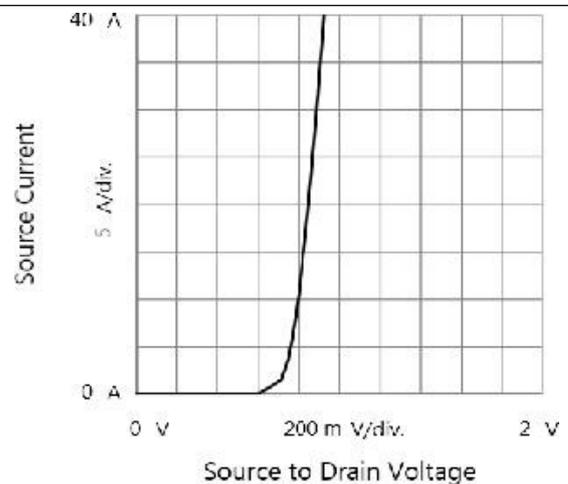


Figure 7. Capacitance

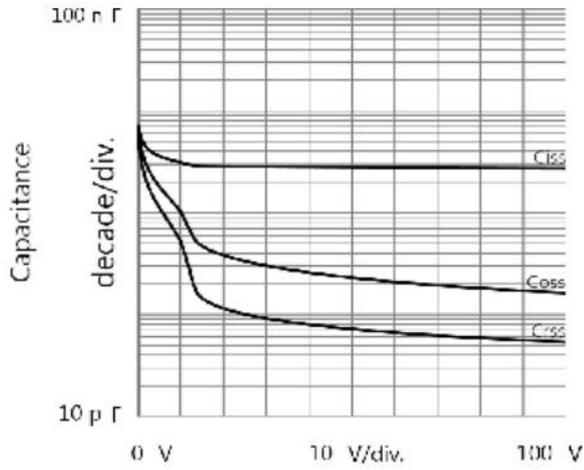


Figure 8. Gate Charge

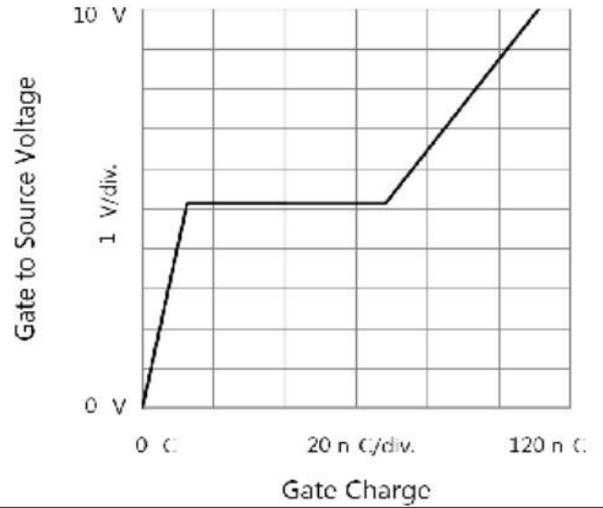


Figure 9. Transient Thermal Impedance (TO-220F)

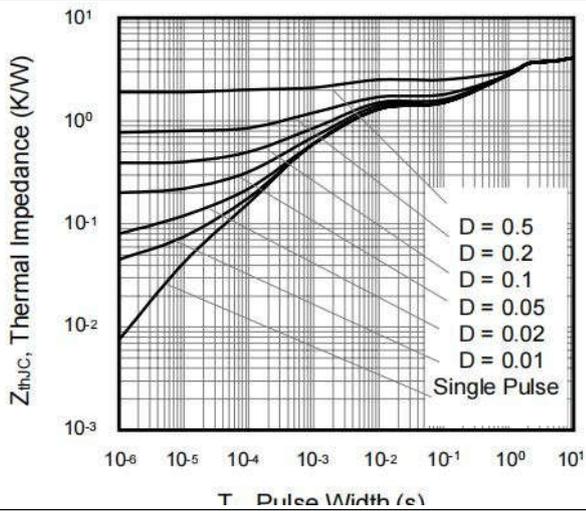


Figure 10. Transient Thermal Impedance (TO-220)

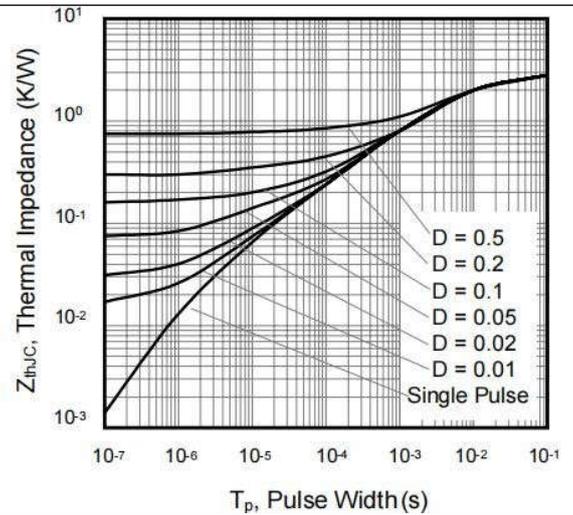


Figure A: Gate Charge Test Circuit and Waveform

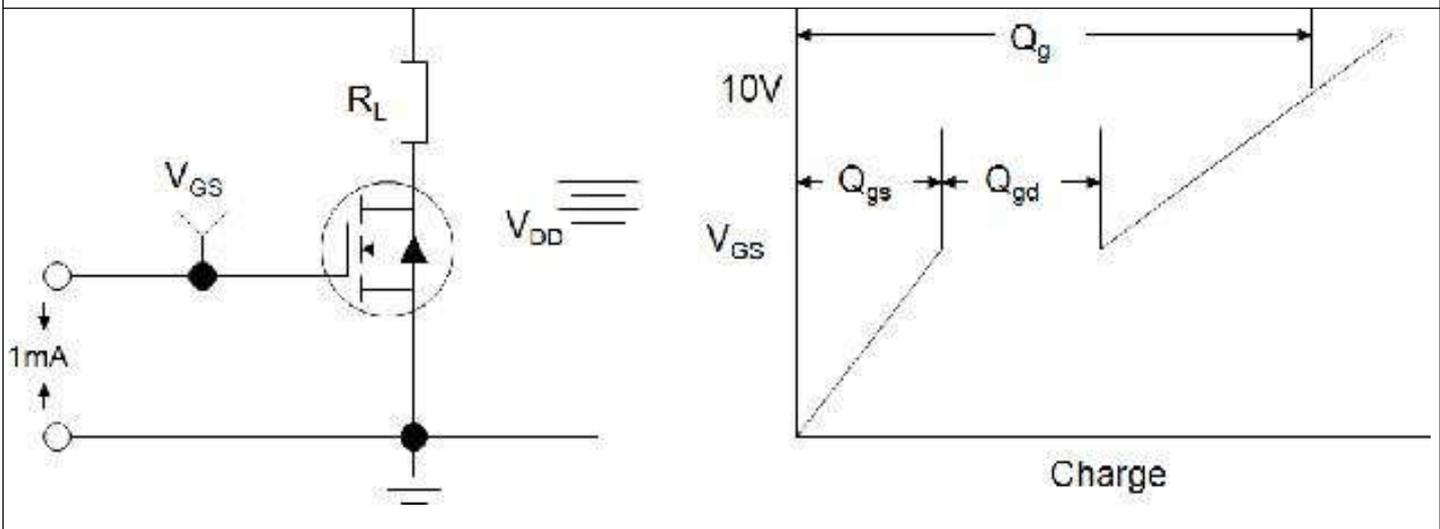


Figure B: Resistive Switching Test Circuit and Waveform

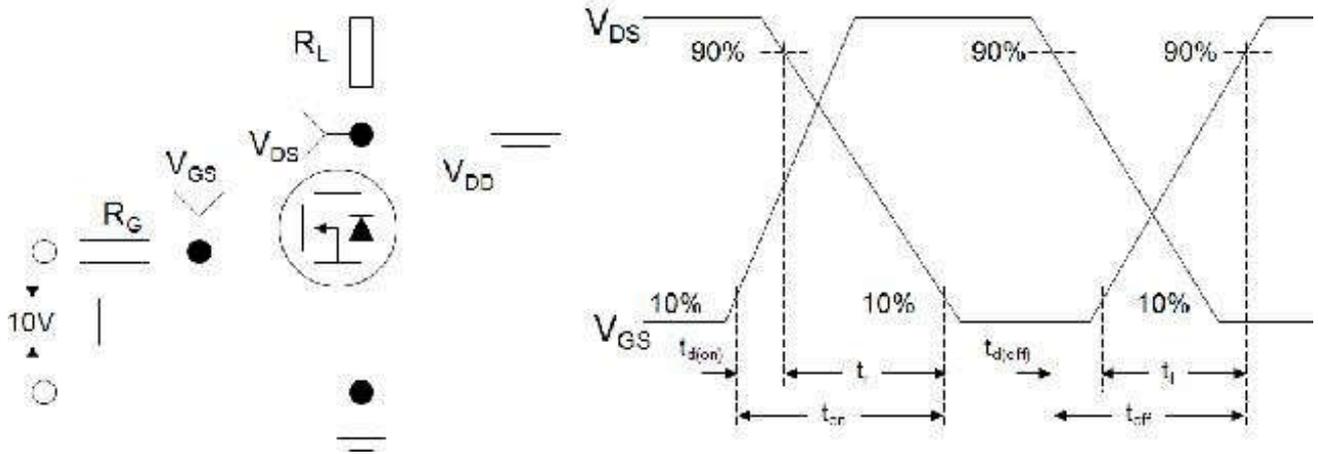
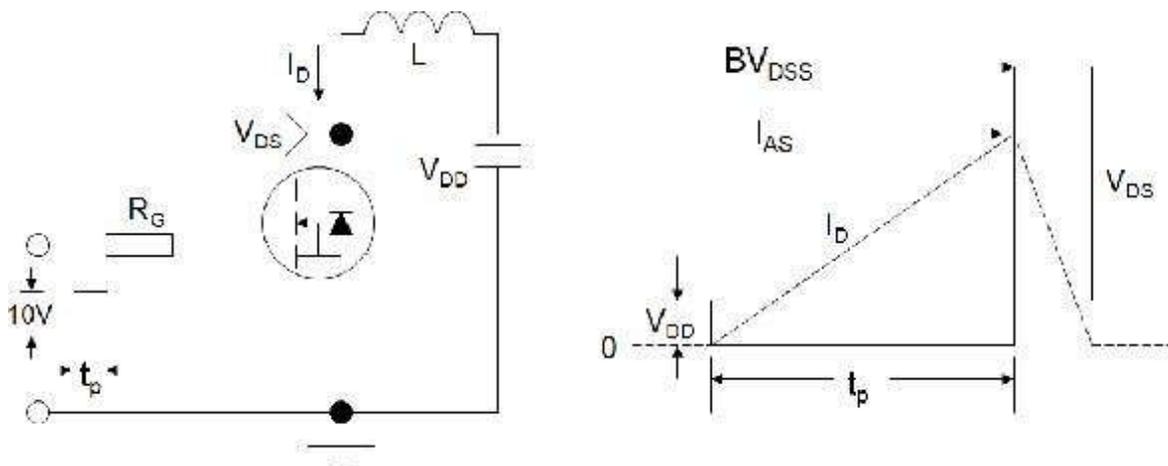
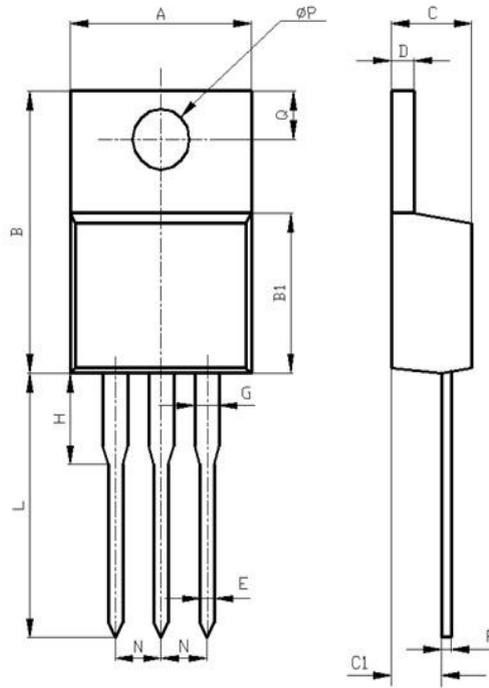


Figure C: Unclamped Inductive Switching Test Circuit and Waveform



Package Description



Items	Values(mm)	
	MIN	MAX
A	9.60	10.6
B	15.0	16.0
B1	8.90	9.50
C	4.30	4.80
C1	2.30	3.10
D	1.20	1.40
E	0.70	0.90
F	0.30	0.60
G	1.17	1.37
H	2.70	3.80
L	12.6	14.8
N	2.34	2.74
Q	2.40	3.00
φp	3.50	3.90

TO-220 Package



NOTE:

1. Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
2. When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
3. MOSFETs is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
4. Shenzhen Minos reserves the right to make changes in this specification sheet and is subject to change without prior notice.

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